

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/054,155 | | Applicant(s)/Patent Under Reexamination DARBIE, WILLIAM P. | |
| | Examiner Maikhanh Nguyen | | Art Unit 2176 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| * | A | US-4,417,322 | 11-1983 | Berry et al. | 715/523 |
| * | B | US-5,754,860 | 05-1998 | McKeeman et al. | 717/124 |
| * | C | US-6,269,460 B1 | 07-2001 | Snover, Jeffrey Phillip | 714/48 |
| * | D | US-6,272,204 B1 | 08-2001 | Amtower et al. | 378/63 |
| * | E | US-6,397,378 B1 | 05-2002 | Grey et al. | 717/175 |
| * | F | US-6,577,981 B1 | 06-2003 | Grey et al. | 702/119 |
| * | G | US-6,825,856 B1 | 11-2004 | Fazzio et al. | 345/646 |
| * | H | US-7,108,424 B2 | 09-2006 | Heumann et al. | 378/207 |
| * | I | US-2002/0042897 A1 | 04-2002 | Klein et al. | 714/718 |
| * | J | US-2004/Q205565 | 10-2004 | Gupta, Arun P. | 715/513 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | "The Complete Testing Solution for E-business", Mercury Interactive, www.merc-int.com, 01/1999, pp: 1-4. |
| | V | Miki Magyar, "Automating Software Documentation: A Case Study", IEEE, 2000, pp: 549-558. |
| | W | "Test and Measurement", http://www.testandmeasurement.com , 10/16/2000, pp: 1-9. |
| | X | S. Grennan, "Application of a commercial data base management system to memory device test program generation and debugging", IEEE, 09/1988, pp. 289-294. |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.